

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

## Title of Invention

STRUCTURE AND METHOD FOR SILICIDED METAL GATE  
TRANSISTORS

Application Number : 10/605,130

Confirmation Number:

First Named Applicant: Bruce Doris

Attorney Docket Number: FIS920030283US1

Art Unit:

Examiner:

Search string: ( 6033963 or 6492694 or 6528362 or 6534352 or 6544827 or 6589866 or  
20030122202 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
DN	1	6033963	2000-03-07	Huang, et al.			
	2	6492694	2002-12-10	Nobel, et al.			
	3	6528362	2003-03-04	Besser, et al.			
	4	6534352	2003-03-18	Kim			
	5	6544827	2003-04-08	Abiko			
DN	6	6589866	2003-07-08	Besser, et al.			

## US Published Applications

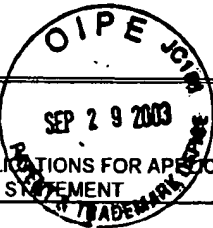
Note: Applicant is not required to submit a paper copy of cited US Published Applications

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
DN	1	20030122202	2003-07-03	Kwon			

Signature

Examiner Name

10/6/04  
Date



FORM PTO-1449 (Modified)	ATTY. DOCKET NO. <b>FIS920030283US1</b>	SERIAL NO. <b>10/605,130</b>
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT: <b>DORIS ET AL.</b>	
(Use several sheets if necessary)	FILING DATE:	GROUP:

## REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	ISSUED DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
					YES NO

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

DN	AH	S.B. Samavedam et al., "Silicon Materials – Processing, Characterization and Reliability Symposium," Mater. Res. Soc. Proc., vol. 716, 2002, pp. 85-90.
I	AI	K. T. Nishinohara et al., "Regular Papers Short Notes & Review Papers" Japan Jnl. App. Phys. Ltrs, pt 1, v. 40, 2001, pp. 2603-2606.
I	AJ	F. F. Zhao et al., "Silicon Materials – Processing, Characterization and Reliability Symposium," Mater. Res. Soc. Proc., vol. 716, 2002, pp. 41-46.
DN	AK	W. T. Liaw et al., "Letters" Japan Jnl. App. Phys. Ltrs, pt 2, v. 36, n. 2A, 1997, pp. L89-92.

EXAMINER <i>Doris</i>	DATE CONSIDERED <b>10/6/04</b>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.